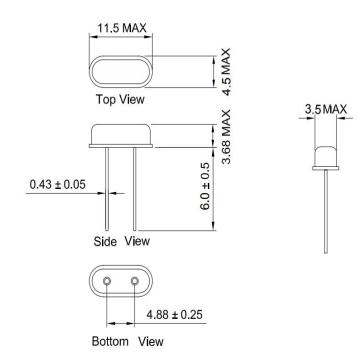


Quartz Crystal Units

1. Specifications:

Parameter	Symbol	Min.	Тур.	Max.	Unit
Oscillation mode	Fundamental				
Cutting mode	AT				
Nominal frequency	f_nom	-	8	-	MHz
Frequency tolerance at 25°C	f_tol	-20	-	20	x 10 ⁻⁶
Stability over temperature	f_tem	-30	-	30	x 10 ⁻⁶
Load capacitance	CL	-	20	-	pF
Motional resistance(ESR)	R1	-	-	60	Ω
Shunt capacitance	C0	-	-	7	pF
Level of drive	DL	-	100	-	μW
Operating temperature	T_use	-20	-	70	°C
Storage temperature	T_stg	-40	-	85	°C
Frequency aging	f_age	-3	-	3	x10 ⁻⁶ /year

2. Dimensions:





3. Reliability characteristic:

NO	Item	Condition	Reference	Specifications
4.1	Solderability	Solder bath temperature:260°C,dwell time:5 seconds,Solder: 100% tin	IEC68-2- 20:1979	A new uniform coating of solder shall cover a minimum of 95% of the surface being immersed.
4.2	Resistance to soldering heat	Solder temperature 260+/-5°C,Immersion time:10 S Solder bath composition:100% tin	IEC68-2- 58:1989	∆F≤+/-5ppm
4.3	Vibration	The entire frequency range: 10Hz to 55Hz ,Amplitude:1.5mm This motion shall be applied for a period of 2 h in each of 3 mutually perpendicular axes(a total of 6h)	IEC 68-2- 21:1992	$\Delta F \leq +/-5 ppm$
4.4	Drop test	Drop from 75cm height on 3cm hard wooden board for 6 times	IEC68-2- 32:1990	∆F≤+/-5ppm
4.5	Cold storage	The quartz crystal unit shall be stored at a temperature of -40+/-3°C for 1000 h.then it shall be subjected to standard atmospheric conditions for 1h after which measurement shall be made.	IEC68-2- 6:1982	∆F≤+/-5ppm
4.6	High temperature High humidity storage(steady state)	The quartz crystal unit shall be stored at a temperature of 40+/-2°C with relative humidity of 95% for 1000h, then it shall be subjected to standard atmospheric conditions for 2h after which measurement shall be made.	IEC60068-2- 1:1990	ΔF≤+/-5ppm
4.7	Thermal shock	The quartz crystal unit shall be subjected to 50successive Change of temperature cycles. Each asshown in table below ,then it shall be subjected tostandard atmospheric conditions for 1h after which measurement shall be made.NOTemperatureDuration1-40+/-3°C15minutes2105+/-2°C15minutes3Transition timeWithin 10 seconds	IEC68-2- 14:1986	ΔF≤+/-5ppm
4.8	Sealing	Helium leakage detector shall used to measure the leakage rate of gas through any faulty seal. Pressure:500Kpa, duration:120 minutes.	IEC68-2- 3:1984	Leakage rate≤ 1*10-9 Pa.m3/S
4.9	High temperature Life test	The quartz crystal unit shall be stored at a temperature of 105+/-3°C for 168h ,then it shall be subjected to standard atmospheric condition for 1h after which measurement shall be made.	IEC60068-2- 2:1974	∆F≤+/-5ppm



4. Disclaimer

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